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**Atomistic study of structure and stability of thin Ni films on Fe surfaces**

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## RESEARCH ARTICLE

## Atomistic study of structure and stability of thin Ni films on Fe surfaces

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The adhesion and residual strain of Ni thin-film coatings on  $\gamma$ -Fe and  $\alpha$ -Fe substrates are investigated by *ab initio* calculations using density functional theory (DFT) in the local density approximation (LDA), and by an empirical Finnis-Sinclair type interatomic potential utilizing angle dependent terms [Mishin *et al.*, Acta Mat. **53** (2005), 2029]. The results from the DFT and empirical potentials agree for strained coherent interfaces. The phase stability and structural transitions are studied for incoherent interfaces via molecular dynamics and static relaxation methods. It is found that the transition in thin Ni films from bcc to fcc structure occurs for 3-4 monolayers and is accompanied by a reorientation of the Ni film with respect to the Fe substrate.

## 1. Introduction

Thin film systems play an important technological role due to their unique mechanical, chemical, and physical properties; thin film systems are found in magnetic storage devices, used as wear resistant coatings, as corrosion protection layers or as thermal barriers. Film systems with specifically tuned properties are designed and used for various applications. In coating applications for example, the main goal is to obtain strong and highly wear and corrosion resistant films that adhere strongly to the substrates. For magnetic storage applications, the main requirement is to design films with stable magnetic structures that do not change due to thermal fluctuations during the device life time. The adhesion, the resilience against wear, and the magnetic properties are closely dependent on the atomistic structure and chemical bonding at the interface between the substrate and the film as well as on the atomistic structure of the film itself.

The adhesion at the interface depends on the interatomic interactions between the substrate and film. In a coherent interface system, where the substrate and film have the same in-plane lattice parameters, the adhesion depends primarily on the chemical bonding [1–3]. Yet, perfect coherency is seldomly encountered, as in general the lattice parameters do not perfectly match, and additional structural terms resulting from the lattice misfit at the interface has to be taken into account. If the interaction between the substrate and film materials is strong enough, then there will be a certain degree of structural matching, or compliance, of the film with

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1 the substrate. This leads on the one hand to a stronger adhesion and lower excess  
2 energy of the interface, but on the other hand it is accompanied by residual stresses  
3 and their corresponding strains in the thin film. The excess energy due to these  
4 stresses may or may not exceed the gain in energy due to bonding. The balance  
5 between the bonding and stresses determines the amount of compliance of the film  
6 to the substrate and its phase stability. Perfect compliance of the film results in  
7 a pseudomorphic phase, where the film assumes the same lattice structure as the  
8 substrate [4].

9  
10 Residual stresses in thin films also originate from manufacturing processes, e.g.,  
11 electroplating, and they may also result at normal operating conditions, for in-  
12 stance when high temperature gradients exist, causing different thermal expansions  
13 of substrate and film and thus a bending of the film. The coupled effect of adhesion  
14 and strain on the macroscopic properties of the thin film system is of crucial im-  
15 portance to the successful design and operation of the device. In general, stresses  
16 in thin films are undesired as they may cause fatigue, delamination, and a de-  
17 crease in performance in corrosive environments. On the other hand, for magnetic  
18 applications, the interplay between bonding and strain leads to various magnetic  
19 properties and phases, and it is therefore an important factor in the design of these  
20 systems (see, e.g., Refs [3, 5]).

21  
22 Fe-based magnetic thin film systems are most widely used for their magnetic  
23 properties, either in single-layer or in multilayer structures (for a recent review, cf.  
24 [6]). In most cases the Fe-containing layers need protection against corrosion, and  
25 Ni is often used for protective coating [6]. Compared to other thin film systems,  
26 the case of Ni films deposited on Fe substrates has been less studied so far, in spite  
27 of its relevance for mechanical and magnetic applications. In particular, theoretical  
28 studies for the interface structure and adhesion for Ni on Fe are rare [6]. In the  
29 current study we investigate the thermal and mechanical stability of thin Ni films  
30 on Fe substrates at temperatures ranging from 0K up to 1200K.

31  
32 The bcc phase of Ni, which does not exist in nature, has been shown by first-  
33 principles DFT calculations [7, 8] to correspond to a metastable phase with an  
34 equilibrium lattice constant of  $a^{bccNi} = 2.78 \text{ \AA}$ , which has a small lattice mismatch  
35 with bcc  $\alpha$ -Fe ( $a^{\alpha-Fe} = 2.866 \text{ \AA}$ , cf., e.g., Ref. [8]). Therefore it is expected that  
36 bcc Ni may grow as a metastable phase on  $\alpha$ -Fe (001). This bcc Ni phase was  
37 obtained by means of molecular beam epitaxy by Heinrich et al. [9, 10] and by  
38 Wang et al. [11]. These experimental results suggest that bcc Ni can be grown  
39 pseudomorphically on the bcc Fe(001) surface with up to 3 [10] or 6 [11] Ni (100)  
40 monolayers, depending on the substrate conditions. Above this thickness the lat-  
41 tice constant expands by 2% and develops a  $c(2 \times 2)$  surface reconstruction. The  
42 unreconstructed and strained bcc Ni films are found to be non-magnetic, while  
43 the reconstructed films are magnetic with four-fold in-plane magnetic anisotropy  
44 and a magnetic moment of approximately  $0.4 \mu_B$ /atom for a 6 nm bcc Ni film on  
45 Fe (001). This demonstrates the close relationship between the atomistic structure  
46 and the magnetic functional properties of the thin film. Moreover it offers a means  
47 for tuning these properties by controlling the growth mode.

48  
49 An investigation of the structural changes in MBE grown Ni/Fe(001) multilayers,  
50 using RHEED and X-ray diffraction by Kamada et al. [12, 13], indicated that  
51 the structure of up to 3 ML of Ni is body-centered-tetragonal (bct) instead of  
52 the expected bcc structure (i.e., bct with  $c/a = 1$ ), and that it has an enhanced  
53 moment of  $0.8 \mu_B$ . Above 3 ML, the structure becomes more disordered, and seems  
54 to resemble that of the reconstructed  $c(2 \times 2)$  structure. Mijiritskii et al. [14, 15]  
55 have suggested, based on a detailed study of the angle dependence of the RHEED  
56 patterns, that this apparent surface reconstruction corresponds instead to the fcc  
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1 Ni phase (i.e., bct with  $c/a=\sqrt{2}$ ) consisting of a mosaic of four different Ni(110)  
2 domains. The same possibility was also considered by Heinrich et al. [9, 10]. At the  
3 thickness where these extra diffraction patterns appear, a martensite-like bcc-Ni to  
4 fcc-Ni transformation may have taken place. Gutierrez et al. [16] observed for an  
5 Fe/Ni multilayer a bcc Ni structure, albeit with weak reconstruction features. This  
6 slight discrepancy in the exact description of the structural phases can be effectively  
7 investigated using atomistic simulations via the Finnis-Sinclair (FS) or the related  
8 embedded-atom-method (EAM) interatomic potentials. We therefore consider here  
9 two types of interfaces between very thin films of up to 25 layers of either bcc or  
10 fcc Ni on Fe. In the first type films of Ni are assumed completely compliant, i.e.,  
11 pseudomorphic with Fe, and in the second type, more general incoherent interfaces  
12 are considered as initial conditions for the structural optimization.  
13  
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15 Experimental data [11–15, 17] suggests that thin films of Ni composed of up to  
16 3 or 4 layers are probably stable in the bcc structure. Systems with more than 4  
17 layers exhibit a structural transformation of the bcc Ni into an intermediate, de-  
18 formed fcc phase. The nature of this intermediate phase, and the specific number of  
19 layers at which the transformation occurs, are not entirely understood. Atomistic  
20 molecular dynamics and static relaxation simulations, for instance with the inter-  
21 atomic potential of Mishin et al. [8], enable an atomistic insight into the structural  
22 changes. We therefore perform such simulations of the structure and stability of  
23 such Ni films on Fe substrates and investigate the structural transformations.  
24

25 This work is divided into two parts. In the first part, the completely compliant  
26 pseudomorphic thin Ni films on both *ferrite*,  $\alpha$ -Fe, and *austenite*,  $\gamma$ -Fe, are exam-  
27 ined for their residual stresses and adhesion using first-principles density-functional  
28 theory (DFT) calculations in the local density approximation (LDA). For compar-  
29 ison, we also consider pseudomorphic interfaces between Cr, which is as well as Ni  
30 used in coating applications, and Fe. In the second part, the methods of molecular  
31 dynamics and static relaxation based on empirical interatomic potentials are used  
32 to study both pseudomorphic and incoherent Ni overlayers on Fe. The Fe-Ni po-  
33 tential developed by Mishin et al. [8], which is an extension of the embedded atom  
34 method (EAM) by additional angle-dependent terms (the EAM-ADP potential) is  
35 used for this study. This potential does not allow modeling of magnetism, although  
36 it does include magnetic contributions to the total energy [8]. Magnetic effects are  
37 thus not explicitly considered.  
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## 41 2. Computational methods

### 42 2.1. *First-principles DFT calculations*

43 The computational first-principles method used in the present study is based on  
44 density functional theory [18, 19] and the local-density approximation for exchange  
45 and correlation (LDA) [20, 21], employing norm-conserving pseudopotentials [22]  
46 and a mixed basis of localized orbitals and plane waves [23–29]. The pseudopotentials  
47 were constructed from all-electron valence states for free atoms according to  
48 Vanderbilt [30]. Plane waves up to the cutoff energy  $E_{pw} = 16$  Rydberg were used  
49 (1 Rydberg = 13.606 eV). Localized functions confined to atom-centered spheres  
50 with radii  $R_{lo} = 2.5$  Bohr (1 Bohr = 0.529 Å) were employed for d valence states.  
51 A Monkhorst-Pack  $8 \times 8 \times 2$  k-point mesh and a Gaussian broadening by 0.2 eV  
52 were used [24, 31]. These parameters led to convergence of differences in surface  
53 energies to less than  $0.05 \text{ J/m}^2$ .  
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55 For the current study, spin polarization is not taken into account. Although  
56 this prevents the extraction of the magnetic properties of these interfaces from the  
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1 results, it does at least allow for a direct comparison between the DFT calculations  
2 and the non-magnetic atomistic simulations using the ADP-EAM potential.

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5 **2.2. Supercell models**

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7 For the DFT calculations, small coherent interface systems are used. The interface  
8 systems of the thin Ni and Cr films on both  $\alpha$ -Fe and  $\gamma$ -Fe substrates are modeled by  
9 slab supercells, consisting of seven atomic (110) and (111) layers for  $\alpha$ -Fe and  $\gamma$ -Fe,  
10 respectively. The thin fcc Ni films are composed of eight atomic (111) layers, while  
11 the bcc Cr films are composed of seven atomic (110) layers. Each atomic layer is  
12 represented by one atom per surface unit cell. Periodic boundary conditions parallel  
13 to the surface and normal to the interface are applied, such that two equivalent  
14 interfaces are present in the systems. The in-plane lattice constants of Ni and Cr  
15 films are fixed due to the interaction with the substrate, while the out-of-plane  
16 lattice parameter is free to adjust to the value that minimizes the free energy  
17 of the system, usually tending to keep the volume of the unit cell approximately  
18 constant (Poisson effect). This is a general phenomenon which is encountered in  
19 solid-solid and even in solid-liquid interfaces [32, 33].  
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24 **2.3. Molecular dynamics and static relaxations**

25 For the atomistic simulations, an EAM-type potential with additional angle-  
26 dependent terms for Fe-Ni developed by Mishin et al. [8] was used. The angle-  
27 dependent terms are added to simulate the bcc phase more accurately. Due to the  
28 absence of magnetism in the potential, but the inherent presence of magnetic effects  
29 in the experimental and ab-initio data to which the potential was parametrized,  
30 this potential tends to show correct bonding in those configurations where a mag-  
31 netic bonding interaction is present, but it shows over-bonding in those configura-  
32 tions where there is no or a negative contribution of the magnetic interaction to  
33 the bonding. The presence of magnetic effects in thin Ni films on Fe is therefore  
34 expected to be reasonably well mimicked.  
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39 **2.4. Ideal work of separation, excess strain and interface energies**

40 The ideal work of separation  $W_{sep}$  is defined as the energy difference per unit  
41 area between an interface system and one where the two surfaces are completely  
42 separated:  
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45 
$$W_{sep} = \frac{E_{film} + E_{substrate} - E_{interface}}{2A} \quad (1)$$
  
46

47 where  $A$  is the interface area,  $E_{film}$  and  $E_{substrate}$  are the energies of separated  
48 film and substrate, and  $E_{interface}$  is the total energy of the interface system. No  
49 relaxation of atomic positions is taken into account. The validity of this approach  
50 has been extensively discussed elsewhere [34, 35].  $W_{sep}$  specifies how much energy  
51 needs to be invested in the system to cause a separation of the interface [36].  
52 The work of separation calculated in this manner gives direct information on the  
53 chemical bonding at the interface.  
54

55 The excess strain energy  $\gamma_\epsilon$  is defined as the energy difference of a strained bulk  
56 crystal with exactly the same strain as in the interface system, and an unstrained  
57 bulk crystal. If the strain components in the film are  $\epsilon_x$  and  $\epsilon_y$ , parallel to the  
58 interface in a coherent configuration, the resulting strain energy per monolayer  
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and unit area is:

$$\gamma_\epsilon = \frac{E^{bulk}(\epsilon_x, \epsilon_y) - E^{bulk}(0)}{nA_\epsilon} \quad (2)$$

where  $E^{bulk}(\epsilon_x, \epsilon_y)$  is the total energy of a strained film, taking into account the relaxation in the direction normal to the interface.  $E^{bulk}(0)$  is the energy of an unstrained bulk crystal (which we consider as the reference chemical potential for the film),  $n$  is the number of layers, and  $A_\epsilon$  is the area of a strained system [37]. Hence, the work of separation represents the chemical contribution to the interfacial bonding, while the structural contributions are given by the excess strain energy [1, 2]. The adhesion of the interface is then analyzed by considering both of these two quantities.

The excess interface energy of the system is expressed as:

$$\gamma = (E - \sum_i n_i \mu_i) / 2A \quad (3)$$

where  $E$  is the total energy of the system,  $n_i$  and  $\mu_i$  are the number of atoms and chemical potential of species  $i$  (the latter referred to the bulk phases of Cr, Fe, and Ni).

### 3. Results and Discussion

#### 3.1. Interface adhesion and mechanical stability of coherent interfaces

In this section, ideal coherent interface models, in which the film is assumed to fit exactly onto either bcc or fcc substrates of bcc  $\alpha$ -Fe and fcc  $\gamma$ -Fe, respectively, are considered. It is expected therefore that unless the lattice parameters of the substrate and film match exactly, a finite amount of strain will be present in the system, which in turn will affect the mechanical interface stability. In this study, the mechanical stability of the system is investigated via the ideal work of separation,  $W_{sep}$ , and the excess strain energy per monolayer in the film,  $\gamma_\epsilon$ , as described in section 2.4.

Four different interface models between Cr, Ni and Fe are considered, thin films of bcc Cr(110) and fcc Ni(111) are deposited onto either the ferrite, bcc  $\alpha$ -Fe(110), or the austenite, fcc  $\gamma$ -Fe(111), substrates. Hence bcc/bcc, fcc/bcc, and fcc/fcc hetero-phase interface models are considered. In the case of bcc/bcc and fcc/fcc systems, the coherent interface was created by straining the lattice parameter of the top layer, taken to be the Cr or Ni film, to the bcc and fcc lattice parameters of Fe, respectively. In the case of fcc (111) Ni on  $\alpha$ -Fe, the fcc unit cell of the film is strained to fit the underlying bcc unit cell of the substrate, but the same ABC stacking of (111) planes as in the fcc system is assumed. Similarly for the case of bcc (110) Cr on  $\gamma$ -Fe, the bcc (110) unit cell of Cr is fitted to the fcc (111) unit cell of  $\gamma$ -Fe, but the AB stacking of (110) planes is assumed. The Nishiyama-Wassermann orientation relationship is used for the bcc-fcc systems, where the  $\langle \bar{1}\bar{1}2 \rangle$  direction on the fcc (111) surface, and the  $\langle 1\bar{1}0 \rangle$  direction on the bcc (110) surface are parallel, and similarly the  $\langle 1\bar{1}0 \rangle$  direction on the fcc (111) surface and the  $\langle 001 \rangle$  direction on the bcc surface are aligned. The lattice parameters of the Ni or Cr layer along these directions were adjusted to the corresponding ones of the Fe substrate. The resulting misfit strains are given in table 2. The in-plane strain,  $\epsilon_x$  and  $\epsilon_y$ , are smallest for the systems with the same lattice structures, namely for fcc Ni on fcc Fe, and for bcc Cr on bcc Fe. In these systems relaxation effects are

1 therefore expected to be small. On the other hand for the pseudomorphic systems  
2 of fcc Ni on bcc Fe, and bcc Cr on fcc Fe, the in-plane strains are large, implying  
3 that large deformations should be expected in the relaxed systems.

4 The interface separation energy, i.e., the negative of  $W_{sep}$ , as a function of the  
5 separation  $\Delta$  between the film and substrate is shown in Figure 1, where the open  
6 symbols are data points from the non-magnetic DFT-LDA calculations and the  
7 lines are fits of the universal equation of state (cf., e.g., [38]). The interface  
8 separation energy calculated using the Fe-Ni EAM-ADP potential of Mishin et al. [8]  
9 is marked by filled symbols. The agreement, as can be seen, is very good, in  
10 particular since such Fe/Ni separation curves were not part of the fitting database [8].  
11 This demonstrates the consistency of the non-magnetic DFT-LDA and the  
12 empirical EAM-ADP for describing the interface bonding. The interface energy at  
13 equilibrium separation  $\Delta$ , i.e.,  $W_{sep}$ , and the excess energy per layer of the film  
14 due to coherency strains,  $\gamma_\epsilon$ , are given in Table 3. From Figure 1 and Table 3 it  
15 is obvious that Cr generally bonds better than Ni to both phases of Fe, regardless  
16 of the strain energy, with  $W_{sep}$  of Cr/Fe being about  $1 J/m^2$  larger than that of  
17 Ni/Fe. Nevertheless, pure Ni is also found to bond rather well to Fe. The chemical  
18 contribution to the interface energy is rather independent of the geometry of the  
19 interface, since nearly the same  $W_{sep}$  is obtained for fcc Ni on either fcc or bcc  
20 Fe, and for bcc Cr on either fcc or bcc Fe. This supports our assumption that the  
21 ideal work of separation  $W_{sep}$  primarily gives information on the bonding at the  
22 interface [34, 35]. However, as given in Table 3 the excess strain energy due to the  
23 coherency is large for the cases of fcc Ni on bcc Fe, and for bcc Cr on fcc Fe. This  
24 indicates that in these systems the Ni and Cr are not stable in their respective  
25 bulk equilibrium structures, which was already expectable from the misfit strains  
26 in Table 2. On the other hand, the strain energy in the bcc/bcc and fcc/fcc systems  
27 is much smaller, implying that indeed in these system the thin films are stable. In  
28 particular for the systems with the same structure, Ni on  $\gamma$ -Fe and Cr on  $\alpha$ -Fe, the  
29 residual strains are small. Table 2 shows the in-plane strains ( $\epsilon_x$  and  $\epsilon_y$ ) calculated  
30 from the lattice parameters in Table 1, and the corresponding Poisson relaxation.  
31 Clearly the systems with the smallest strain energy per monolayer are the ones with  
32 the smallest coherency strains. The larger strain energy for Cr on  $\gamma$ -Fe indicates  
33 either that bcc Cr will be unstable on Fe and will probably dewet, leaving perhaps  
34 a few pseudomorphic monolayers, similar to what has been observed for Cu-Ta  
35 recently by both DFT calculations and molecular dynamics simulations [35, 39],  
36 or that it would assume a pseudomorphic bcc structure.

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44 **3.2. Structure and stability of Ni overlayers on  $\alpha$ -Fe(100)**

45 The work of separation calculations in the preceding section demonstrated a very  
46 good agreement between the EAM-ADP interatomic potential for Fe-Ni of Mishin  
47 et al. [8] and the non-magnetic DFT-LDA calculations. In this section, the inter-  
48 atomic potential is used to move away from the constraints of coherent models  
49 used in the DFT calculations above, in order to investigate the atomistic structure  
50 and thermodynamic stability at a larger length scale for commensurate interface  
51 models between unstrained Ni and  $\alpha$ -Fe.

52 There are no straightforward means to directly obtain the ground-state structure  
53 of a heterophase interface from an atomistic simulation. This is due to the difficulty  
54 to sufficiently sample a huge configuration space in a reasonable simulation time.  
55 Instead, one normally considers a subset of few representative interface models  
56 which are expected to be near to and exhibit similar characteristics as the true  
57 ground-state structure. One route to obtain such models is to choose some initial  
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1 reference configuration based on an ideal lattice structure with a specific energetically favorable orientation relationship. This reference structure is subsequently optimized.

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5 As the number of atoms in a Ni or Fe layer at or near the interface is not necessarily equal to that in the bulk volume, the simulated optimization procedure requires an effective algorithm that allows diffusion of atoms away from or towards the interface region. This is not readily possible in MD simulations with fixed number of atoms in bulk interfaces, because the displaced atoms would become interstitial, instead of reaching the surface for example. Also, diffusion processes occur on the time scale of seconds or minutes, and are difficult to access on the short time scale of atomic vibrations in molecular dynamics simulations.

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13 Gumbsch et al. [1] used the vacancy formation energy in the region of the interface as a criterion for choosing the atoms which should be removed. Atoms with negative vacancy formation energies lead to a reduction of the total energy of the system when removed from the system and hence do not belong to the interface region. The authors demonstrated that a ground-state interface for a Ni-Ag interface can be obtained by removing two [110] rows of atoms from the Ni side, which renders all vacancy formation energies positive, and gives rise to misfit dislocations at the interface.

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22 Von Alfthan et al. [40] used a different approach, in which atoms were picked randomly from twist grain boundaries in Silicon, and the samples were subsequently annealed at various temperatures. In this way, the authors were able to find an ordered low-energy structure for the  $\Sigma 5$  twist grain boundary, which was subsequently confirmed by first-principles DFT calculations.

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35 Recently, Hashibon et al. [41] implemented a method which combines both the calculation of the vacancy formation energy profile and the “random” removal of atoms accompanied with annealing protocols to study the interface structure in Cu-Ta systems. It was shown that both approaches lead to the same result for the ground-state interface structure, which was found to be characterized by a single Cu layer at the interface having mixed fcc-bcc features that facilitate the structural transition from bcc Ta to fcc Cu structures.

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*3.2.1. Kinetic approach to ground-state interface models*

In the present work, we take a different, more straightforward approach which requires neither the random removal of atoms nor the calculation of the vacancy formation energy profiles to find ground state structures of ultra thin-film systems.

First, we choose two initial reference structures for Ni films on an  $\alpha$ -Fe (100) substrate. In the first one a bcc Ni film and in the second one a fcc Ni film are deposited on bcc Fe. The former represents one extreme case where the Ni film is in a state of complete coherency and compliance with the underlying structure of the Fe substrate. The latter represents the opposite extreme case, where Ni is in a state of complete incoherency and non-compliance. Naturally none of these reference structures corresponds a priori to a ground state, but both should be sufficiently close to it. The bcc structure is expected to be the ground state for a sufficiently thin film, or at least in the immediate vicinity of the bcc-Fe surface. The fcc structure is expected to be the ground state for a sufficiently thick film, at least sufficiently far away from the interface, where the structure in the film approaches that of the stable phase of bulk Ni.

Second, systems with varying numbers of Ni layers are introduced for each reference structure as starting configurations. The number of layers considered ranged between 1 and 25 fcc or bcc layers of Ni on the bcc  $\alpha$ -Fe (001) substrate. This enables the analysis of the stability and structure as a function of the thickness of the film.



1 Finally, each of the starting configurations is subject to annealing protocols  
 2 at four different target temperatures:  $T = 300\text{K}$ ,  $600\text{K}$ ,  $900\text{K}$ , and  $1200\text{K}$ . Al-  
 3 though these temperatures are much lower than the melting points for bulk Ni,  
 4  $T_m = 1805\text{K}$ , and Fe,  $T_m = 2135\text{K}$ , as calculated with the current interatomic  
 5 potential [8], substantial thermal disorder is observed in the films during the simu-  
 6 lations. In particular for  $T > 600\text{K}$ , strong disorder occurred in few cases, destroying  
 7 memory of the initial structures to a large extent. As expected [8], at higher tem-  
 8 peratures a substantial mixing between Fe and Ni occurred, which we wanted to  
 9 avoid as much as possible during the annealing. Hence the maximal temperature of  
 10 the annealing protocol was not increased beyond  $1200\text{K}$ . The equations of motion  
 11 were integrated using the Nose-Hoover thermostat with a time step of 2 fs, for a  
 12 total of 4.7 ns, using the IMD program package [42]. At the end of a heating phase,  
 13 the system is quenched, and the temperature is gradually reduced to room temper-  
 14 ature. Finally, an energy minimization using conjugate gradients is performed at  
 15  $0\text{K}$ . Each relaxation is carried out until the total forces on all atoms are less than  
 16  $10^{-4}$  eV/Å. A total set of 64 different initial systems and temperature protocols  
 17 was treated in this manner.

20 These simulations provide by no means a comprehensive sampling of the config-  
 21 uration space. But they do provide means for effectively inspecting the approach  
 22 of the systems to its ground state, starting from different initial conditions. By  
 23 careful comparison of the paths and the final relaxed systems, we obtain valuable  
 24 information regarding the phase stabilities and the ground-state structures. If suf-  
 25 ficiently annealed, it should be expected that all starting configurations will result  
 26 in equivalent, or at least similar final structures having low energies.

### 27 3.2.2. Initial interface models

28 In addition to the coherent bcc/bcc interfaces from section 3.1, we consider now  
 29 two orientation relationships for fcc Ni on  $\alpha\text{-Fe}$  (001) interfaces as initial configu-  
 30 rations. The first orientation relationship (OR I) is a simple cube-on-cube system:  
 31 Ni (001)  $\langle 100 \rangle // \alpha\text{-Fe}(001) \langle 100 \rangle$ , schematically shown in Figure 2(a). The second  
 32 orientation relationship (OR II) is the one reported by experimental studies [12–  
 33 14, 14]: Ni (110)  $\langle 1\bar{1}2 \rangle // \alpha\text{-Fe}(001) \langle 110 \rangle$ , as schematically shown in Figure 2(b). In  
 34 addition to the surface unit cells, few of the nearest neighbor (NN) distances along  
 35 high symmetry directions are indicated on the figure.

36 The  $\alpha\text{-Fe}$  substrates are composed of up to 60 bcc (001) layers, the positions of  
 37 the lowest 4 layers of the Fe were fixed. The top 1 to 25 layers were substituted  
 38 with layers of Ni in either coherent bcc configurations at the same orientation or  
 39 incoherent fcc configurations corresponding to either OR I or OR II. System sizes  
 40 of up to approximately 50,000 atoms were used.

41 Commensurate interfaces for the fcc-Ni/bcc-Fe incoherent systems are con-  
 42 structed such that negligible misfit strains exist in the initially fcc Ni films and  
 43 bcc Fe substrates. For OR I,  $22 \times 22$  fcc (001) Ni surface unit cells are fit to  $27 \times 27$   
 44 bcc (001) Fe surface unit cells, resulting in misfit strain of less than 0.05%. For OR  
 45 II,  $16 \times d_{[211]}$  and  $6 \times d_{[111]}$  Ni planes were matched to  $17 \times d_{[110]}$  and  $9 \times d_{[111]}$  Fe  
 46 planes ( $d$  is the interplanar spacing). In the case of a bcc-film system, the strain in  
 47 the film will eventually lead to an instability of the system and cause a structural  
 48 transformation, resulting in the formation of either a bcc, bct, or another inter-  
 49 mediate distorted fcc phase. In the incoherent case the restructuring of the film is  
 50 expected to be driven by the incoherency, which results in certain atoms to be at  
 51 unfavorable on-top positions. In both cases, the initial number of atoms per layer  
 52 near the interfaces is in general not equal to that for the ground state. This will  
 53 lead to an enhanced restructuring and diffusion, which is expected to reveal certain  
 54 trends in the approach of the system towards equilibrium.

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### 3.2.3. Structural transformations in thin films

The result for the annealing of the fcc system with 1 ML of Ni on Fe is demonstrated in Figure 3 where [010] projections of the initial, unrelaxed system, the relaxed configuration at 0K, and the relaxed configurations resulting after annealing at the various temperatures, are shown. The fcc Ni ML illustrates restructuring already at 0K as it can be seen by comparing the initial unrelaxed system in Figure 3(a) and the system after relaxation in Figure 3(b). This restructuring leads to the formation of small islands on top of a transformed first layer. As the excess atoms are expelled from the fcc layer, the remaining atoms transform the film into a bcc structure. Hence, the initial fcc ML structure of the Ni film results in a transformation to a bcc ML structure with additional islands adsorbed on top. In the corresponding system of a bcc ML of Ni on a bcc Fe, the layer remained bcc until the highest annealing temperature was reached, where mixing was observed. That is, the pseudomorphic bcc Ni ML is stable up to 900K. Only at the highest considered temperature of 1200K does the Ni layer get completely absorbed into the Fe substrate.

For the systems with initially 1-3 ML of bcc Ni, no structural transitions occurred, apart from a change in the interplanar separation normal to the interface. The models with initially 1-3 ML of fcc Ni, on the other hand, do transform. Figure 4, shows a [010] projection of the initial and final relaxed and annealed systems for 3 ML of fcc Ni on bcc Fe. The fcc-Ni film remains stable against relaxation at 0K and annealing at 300K, but transforms after annealing at 600K and above into a bcc-Ni phase.

In both the initial bcc films and the transformed fcc films for the systems with 1-3 ML of Ni, the interplanar separation in the ground-state Ni films is found to be  $d = 1.38 \text{ \AA}$ , in accordance with the value found experimentally  $d = 1.35 \text{ \AA}$  by Kamada and Matsui [12]. Figure 5 shows a [001] projection (a Moiré pattern) of the first Ni layer (gray) on an ideal Fe bcc (001) layer (black). The Ni atoms are located on almost the same positions as the Fe atoms underneath, i.e., the film has a bcc (001) structure. The average in-plane nearest-neighbor (NN) distance is found to be  $a = 2.7 \text{ \AA}$ , smaller than  $a = 2.81 \text{ \AA}$  of a bcc-Ni phase, with a ratio  $c/a = 1.022$ . Hence the structure is body-centered tetragonal (bct) which is only slightly distorted from the cubic bcc structure.

The systems with initially 4 bcc-Ni ML also show no transformation of the bcc-Ni structure, but do show a network of misfit dislocations near the interface region. The system with initially 4 fcc-Ni ML transforms to the bcc structure, also with a network of misfit dislocations. These dislocations at the interfaces will be further discussed elsewhere.

### 3.2.4. Excess interface energy

For each of the systems, the excess interface energy  $\gamma$  is calculated according to equation 3. The results are shown in Table 4 for the first 4 ML for all systems after annealing, and in Figure 6 for bcc Ni and OR I as a function of the initial number of layers in the systems. The dashed lines in the figure connect data points for the systems with initial fcc-Ni structures, and solid lines for the initial bcc-Ni ones. The chemical potential of Fe in equation 2 is taken from the bulk region in the center of the substrate, while for Ni, the cohesive energy of relaxed bulk crystal is used. The excess energy  $\gamma$  includes the excess energy due to the Fe-Ni interface, the deviation of Ni from the fcc structure (i.e., strain energy), the free surface energy of the Ni film, and any island formation or additional defects in the system. Only the energies of the relaxed and annealed systems are shown. Also indicated in the figure is the surface energy of the free bcc (001) Fe surface ( $\gamma = 2.17 \text{ J/m}^2$ ) by an



1 arrow on the abscissa.

2 There are clearly two distinct regimes of the behaviour of the excess interface  
3 energy of OR I in Figure 6. In the first regime, below 3-4 ML, both the fcc and the  
4 bcc initial systems have relatively low interface excess energies, which are almost  
5 equal, except for the systems with 3 and 4 initial fcc-Ni ML at 0K and 300K  
6 (the 'x' and '+' symbols in Figure 6), for which the annealing did not result in a  
7 complete transformation. In fact, if the fcc curve (dashed lines) is shifted by one  
8 ML unit to the right along the x-axis, the dashed and full curves almost coincide  
9 in this regime. This is a result of the structural transformation in these systems  
10 as demonstrated in Figure 3 for the fcc 1 ML and Figure 4 for the fcc 3 ML films,  
11 where an additional layer was generated during the transformation from fcc to bcc  
12 (or bct with  $c/a \approx 1$ ). This is because the fcc-Ni layers have excess of atoms with  
13 respect to the bcc-Fe substrate (968 in the fcc (001) Ni compared to 729 in the  
14 bcc (001) Fe). The compliance of thin films of up to 4 ML, drives the excess atoms  
15 of the initially perfect fcc layers to move out of the interface region and form new  
16 adlayers or islands. The remaining atoms at the interface get restructured into a  
17 bcc phase.

18 The instability of the 1 ML fcc-Ni on the bcc-Fe (001) substrate shown in Figure 3  
19 is of course expected, and it can also be seen from the excess interface energy  $\gamma$  for  
20 1 ML shown in Figure 6 (the first point on the dashed line, with a '+' symbol),  
21 where the excess energy of the relaxed fcc ML at 0K,  $\gamma = 2.22 J/m^2$ , is larger than  
22 that of 1 ML of bcc Ni,  $\gamma = 1.844 J/m^2$ . By inspecting the energies of the various  
23 systems for 1 ML in Figure 6, it is evident that apart from the fcc ML at 0K the  
24 excess energies of a single Ni layer, at all temperatures for both fcc and bcc films,  
25 are significantly lower than the free surface energy of  $\alpha$ -Fe (001) (indicated by an  
26 arrow at the y-axis in Figure 6). Hence, a ML of Ni on Fe is thermodynamically  
27 stable and completely covers the Fe surface.

28 Adding a second bcc or fcc ML of Ni leads to a relatively small increase of the  
29 excess interface energy, of the order of  $0.1 - 0.3 J/m^2$ , as seen from Figure 6 and  
30 Table 4. This increase is not large enough to render two or more ML unstable, since  
31 it is of the same size as for adlayers (cf. the energies of the annealed OR I systems  
32 which do contain adlayers, with the bcc systems which do not in Figure 6.).

33 Notice that our method, since it does not account for the removal of atoms,  
34 may not be sensitive enough to reveal whether a layer-by-layer growth mode is  
35 favorable, although a similar approach with a similar potential [39] did lead to  
36 dewetting for the Cu-Ta system. Nevertheless, our goal in the present work is to  
37 investigate structural trends in the layers adjacent to the interface. Hence the excess  
38 energies, which include additional defects, are not most appropriate to determine  
39 the thermodynamic stability of the films.

40 As seen in Figure 6, for more than 3-4 ML the excess energy of the bcc systems  
41 increases linearly with the number of ML for all temperatures. Assuming this in-  
42 crease is a result of strain, the slope of the line is, by definition, the excess strain  
43 energy per layer in the system. In the same region, the fcc phase seems stable with  
44 respect to the annealing protocols used here, since the excess energy becomes nearly  
45 constant. This implies that no additional contributions to  $\gamma$  exist apart from those  
46 arising from the interface energy and from the free surface energy of Ni, which does  
47 not depend on the number of ML in between (their energy is bulk like, and hence  
48 cancel out, cf. Equation 3). We cannot exclude the possibility that these systems  
49 are already too large and in such deep local minima, that the annealing protocols  
50 used here were too short in time to allow for any transformation. In fact, for the  
51 fcc systems with 5 and more ML, it was apparent that the high energies of the Ni  
52 atoms at the interface induced an enhanced mixing of Ni and Fe at the interface,  
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1 and the formation of a fcc Fe-Ni phase on the Fe side. Adding more Ni layers to  
2 this system did not change the interface region, therefore we neglect these systems.  
3 Nevertheless, it is rather surprising that the switch in behaviour occurred both for  
4 the fcc and bcc initial configurations at the same thickness of 3-4 ML which is also  
5 observed in experiments [11–15, 17].  
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### 7 3.2.5. *In-plane structural relationships*

8 We next take a closer look at the in-plane structure of the 3 ML fcc-Ni system.  
9 The in-plane structure is investigated via the two-dimensional radial distribution  
10 function (2DRDF) calculated for each layer, which is the same as the usual RDF,  
11 (cf., e.g., Ref. [43]), except that each layer is considered as a two-dimensional  
12 structure with projected distances on the plane of the layer. The 2DRDF gives  
13 information about the neighbour shells within each layer. Hence it can directly  
14 reveal structural relations and trends before the actual structure has even emerged,  
15 i.e., before directional order sets in.  
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17 The 2DRDF of the Ni layer directly on top of the substrate in the ground-state  
18 of the system with initially 3 fcc-Ni ML is shown in Figure 7, together with the  
19 2DRDF of ideal bcc-Fe (001), fcc-Ni (001), and fcc-Ni (110) planes, marked on the  
20 figure by solid, dashed, and dotted lines, respectively. The NN shells marked by  
21 “A” and “B” on Figure 7 exist only in the fcc-Ni (110) plane, while the NN shell  
22 marked “C” on the figure exist only in the fcc-Ni (001) plane. We note first that in  
23 spite of the compliance of Ni to the bcc structure of Fe, as evident from the (001)  
24 projection in Figure 5, the layer has a distorted bcc in-plane structure with many  
25 interatomic distances close to those in fcc Ni. These distortions are seen from the  
26 shifts of the NN distances in the 2DRDF in Figure 7. The position of the first peak  
27 in the Ni layer in Figure 7 shifts towards a larger value, closer to that of the first  
28 NN distance in a bulk bcc (001) Fe plane, indicating a line matching along  $\langle 100 \rangle$   
29 directions. The peak corresponding to the third NN distance of fcc-Ni (001) planes  
30 ( $d_{3NN} = 4.98 \text{ \AA}$ ), is completely absent from the 2DRDF of the Ni layer. Instead  
31 there is a peak near the bcc (001) second NN distance ( $d_{2NN} = 4.05 \text{ \AA}$ ). However  
32 this peak is also close to the third NN distance in fcc-Ni (110) planes (at  $4.3 \text{ \AA}$ ,  
33 cf. Figure 2(b)). This indicates line matching along the  $\langle 112 \rangle$  in fcc Ni directions,  
34 corresponding to the  $\langle 110 \rangle$  directions in bcc Fe. Finally, a peak in the 2DRDF of Ni  
35 is also found at the fifth NN distance (at  $6.1 \text{ \AA}$ , cf. Figure 2(b)), which corresponds  
36 to the  $\langle 111 \rangle$  direction in a fcc (110) Ni layer.  
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38 These interface-specific peaks marked A and B in Figure 7 and the shifts in  
39 the second NN distances, indicate a possible preferred direction for line matching  
40 between fcc Ni and bcc Fe, which is independently obtained from the bcc/bcc  
41 interfaces and from those of fcc Ni on bcc Fe in OR I. In particular, the two peaks  
42 A and B are typical of a (110) fcc-Ni plane, with the  $\langle 1\bar{1}2 \rangle$  fcc-Ni direction parallel  
43 to the  $\langle 1\bar{1}0 \rangle$  bcc-Fe direction, which is exactly the orientation OR II. Hence by  
44 starting with either OR I, or coherent bcc/bcc interfaces, the trends in the 2DRDF  
45 suggest that OR II is more favourable.  
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47 We note that the 2DRDF gives only averaged distances of neighbouring shells  
48 and does not indicate directional order. Hence, although the nearest-neighbour  
49 distances may be compatible with those of a (110) plane, the interface may not  
50 necessarily be of (110) type, as seen by comparing Figures 5 and 7. In fact, such a  
51 transformation will not appear since the size of the system is constrained to that  
52 of OR I. Indeed for the thicker films, large strains are found in the systems, as also  
53 indicated by the regime of linear increase in Figure 6 for the bcc systems.  
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55 The OR II systems are already constructed such that  $\langle 1\bar{1}2 \rangle$ -fcc is parallel to  
56  $\langle 110 \rangle$ -bcc. Figures 8 and 9 demonstrate similar but more pronounced features in  
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OR II as compared to OR I. For the case of the 2 ML system, shown in Figure 8, the Ni film is transformed into bcc, where the first as well as the second NN distances are very close to those of bcc Fe. For the 4 ML case shown in Figure 9, the second NN distance is now larger than that in bcc Fe, and it is close to that found in fcc (110) Ni planes. Our results indicate therefore that for thicker Ni layers, a transition from bcc-Ni to fcc-Ni with OR II should occur. This is in agreement with findings in Refs. [14, 15], where X-ray diffraction experiments on OR I samples confirmed the transition to OR II. Hence, we have shown here that the kinetic approach to ground-state structures and the 2DRDF provide a simple but powerful route to determining orientation relationships in heterophase interfaces.

#### 4. Conclusion

We have performed atomistic simulations for coherent Fe/Ni interfaces and for thin Ni films on the bcc  $\alpha$ -Fe (001) substrates, using both DFT-LDA and atomistic simulations with an angle-dependent embedded-atom-method potential. Our results indicate that the used EAM (or Finnis-Sinclair type) potentials [8] with additional angle-dependent terms describes the interface adhesion of Ni-Fe systems for coherent interfaces in good agreement with ab-initio calculations. We then attempted to study the structural trends in thin films by means of kinetic simulations, without the need to calculate vacancy formation profiles or random removal of atoms. We demonstrated that this procedure, although it is not rigorous and has its limitations, can nevertheless be quite effective in identifying the favourable orientation relationship of incoherent interfaces by inspection of the main trends along the relaxation paths of different initial structures. The favourable orientation relationship which we obtained is also observed experimentally. We also found that up to 3-4 layers thin Ni films on Fe are stable in a slightly distorted bcc structure, in agreement with experiments, and that they undergo a transition to the fcc structure with increasing number of layers. We demonstrated that the transition occurs gradually by changing the first and third nearest neighbour distances in fcc Ni.

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System	a(DFT)	a(EAM)	a(EXP)
$\alpha$ -Fe	2.72	2.8665	2.8665 <sup>a</sup>
$\gamma$ -Fe	3.41	3.483	3.64 <sup>b</sup>
fcc-Ni	3.45	3.52	3.52 <sup>a</sup>
bcc-Cr	2.85	-	2.88 <sup>a</sup>

Table 1. The cubic lattice parameters calculated in this work by DFT-LDA, compared to EAM-ADP results (from reference [8]), and experimental values from <sup>a</sup> [44] and <sup>b</sup> [45]

Substrate	Film	$\epsilon_x$	$\epsilon_y$	$\epsilon_z$
$\alpha$ -Fe(110)	Ni(111)	11.5	-8.9	-0.89
$\alpha$ -Fe(110)	Cr(110)	-3.1	-3.1	3.46
$\gamma$ -Fe(111)	Ni(111)	-1.2	-1.2	0.48
$\gamma$ -Fe(111)	Cr(110)	-14.1	5.18	6.66

Table 2. Residual strains in the coherent interface models obtained by comparing the energies of the coherent models and ideal bulk crystals obtained from the DFT-LDA calculations.

Interface model	$W_{sep}$ $J/m^2$	$\gamma_\epsilon$ $J/m^2$	$\Delta$ $\text{\AA}$
$\alpha$ -Fe(110)-Ni(111)	5.5707	0.25	3.69
$\alpha$ -Fe(110)-Cr(110)	6.8500	0.06	3.72
$\gamma$ -Fe(111)-Ni(111)	5.6885	0.0024	3.78
$\gamma$ -Fe(111)-Cr(110)	6.5945	1.05	3.89

Table 3. The ideal work of separation, excess strain energy per monolayer (ML), and equilibrium interface separation for the coherent interface models obtained from DFT-LDA calculations.

ML	bcc	OR I	OR II
1	1.84	1.97	1.91
2	2.13	2.25	2.18
3	2.28	2.40	2.30
4	2.36	2.56	2.42

Table 4. Excess interface energy  $\gamma$  in  $J/m^2$  for 1 to 4 ML of Ni on  $\alpha$ -Fe (001) surfaces obtained from atomistic EAM-ADP simulations. Only the energies of ground-state interface structures are given.

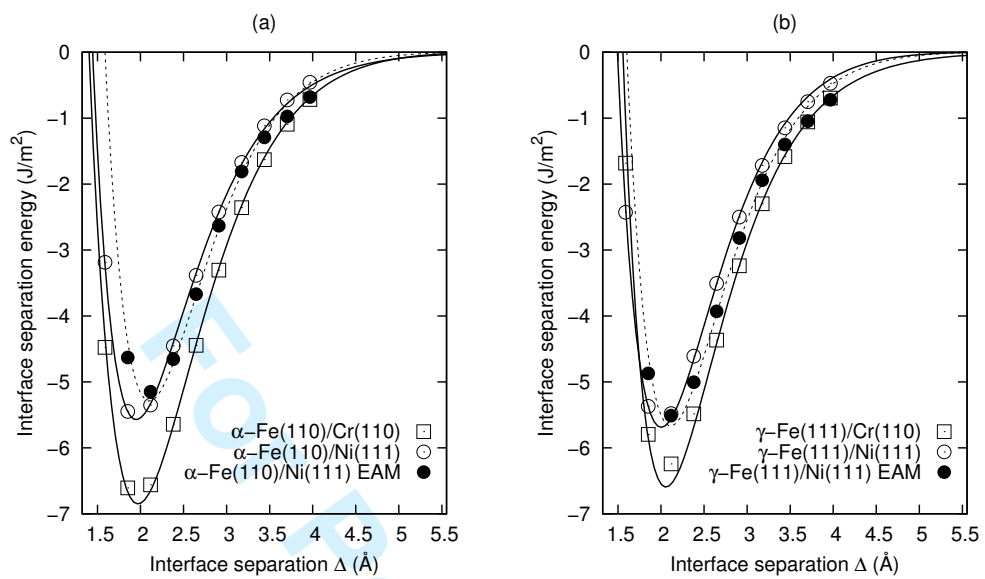


Figure 1. The interface separation energy curves for bcc Cr and fcc Ni on bcc α-Fe (left panel) and fcc γ-Fe (right panel) from DFT-LDA calculations (open symbols) and EAM-ADP simulations (filled symbols).



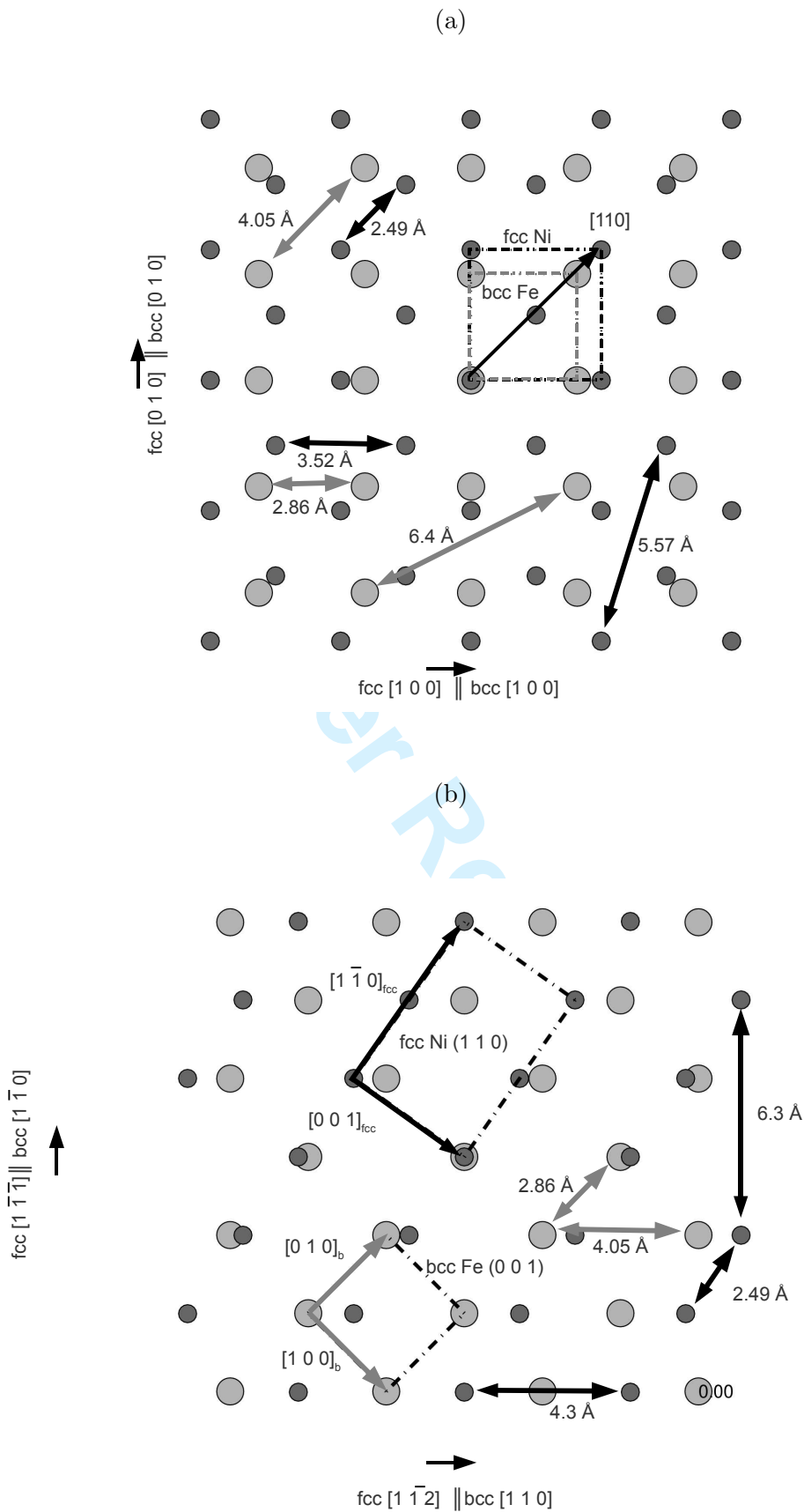


Figure 2. A schematic representation of the interface structure for interface orientation relationships (a) OR I, and (b) OR II. The surface unit cells of fcc-Ni and bcc-Fe are shown in the figure. The numbers state the distances in special symmetry directions. See text for more details.



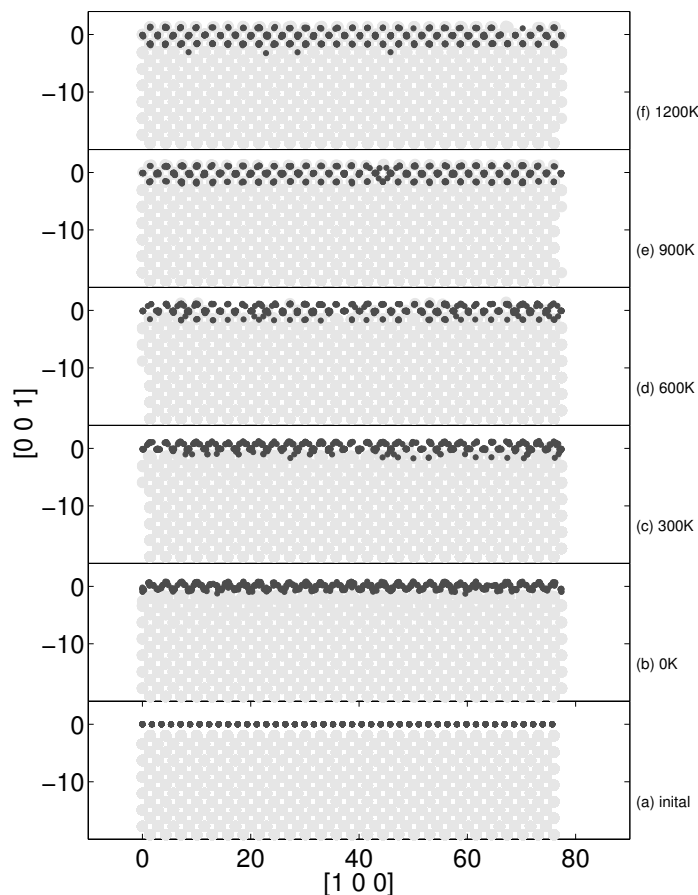


Figure 3. A view of systems with 1 ML of fcc Ni on the (001) surface of bcc Fe in ORI projected along [010]: (a) the initial unrelaxed system, (b) the relaxed configuration at 0K, and (c-d) the relaxed configurations resulting after annealing at the various temperatures, as indicated on the Figure. As a result of the annealing, already at  $T=300\text{K}$  (c) small islands form on the surface. At high temperatures (d-f), Ni atoms are driven into the Fe sublattice to lower energy, and strong mixing of Ni and Fe occurs.

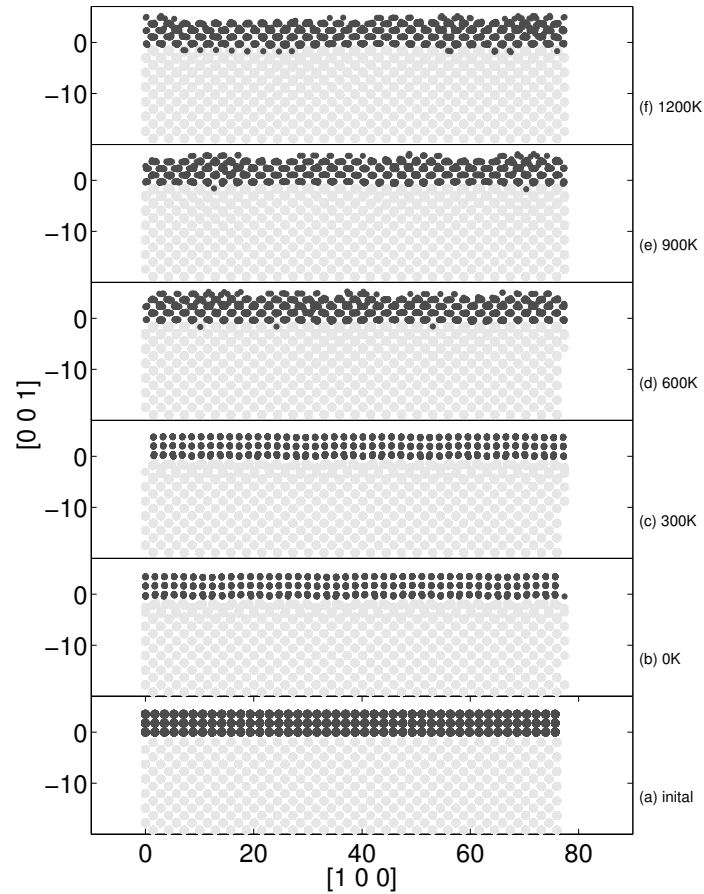


Figure 4. A view of systems with 3 ML of fcc Ni on the (001) surface of bcc Fe in ORI projected along [010]: (a) the initial unrelaxed system, (b) the relaxed configuration at 0K, and (c-d) the relaxed configurations resulting after annealing at the various temperatures, as indicated on the Figure. The annealing enables the fcc-Ni layer to transform into a bcc-Ni layer (d-f), reducing the planar density, and resulting in an additional incomplete bcc layer.

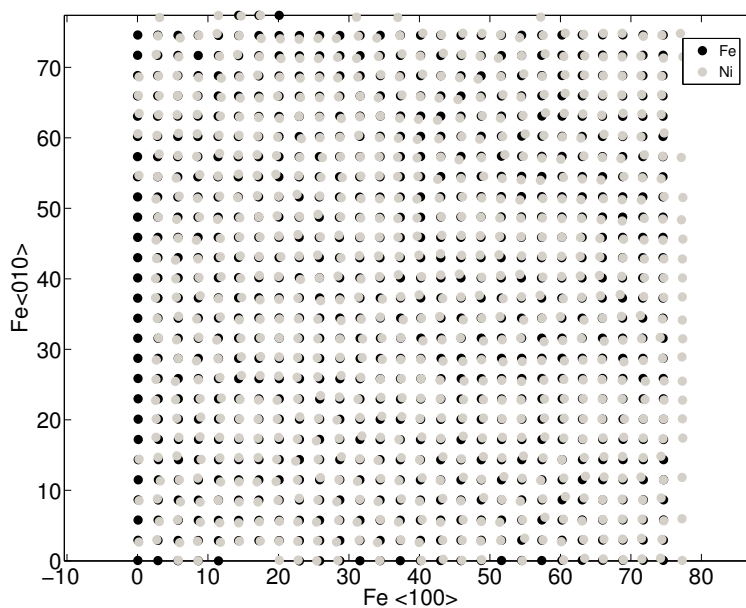


Figure 5. The structure of the Ni layer directly at the interface in the ground state of the system with initially 3 ML of fcc Ni, shown in a projection along the normal direction to the interface (001). The Ni layer (grey symbols) is superimposed on the bcc-Fe (001) layer (Black symbols). The atoms of the Ni are found almost directly on top of the bcc-Fe (001) positions, indicating a bcc structure of the Ni layer in the ground state.

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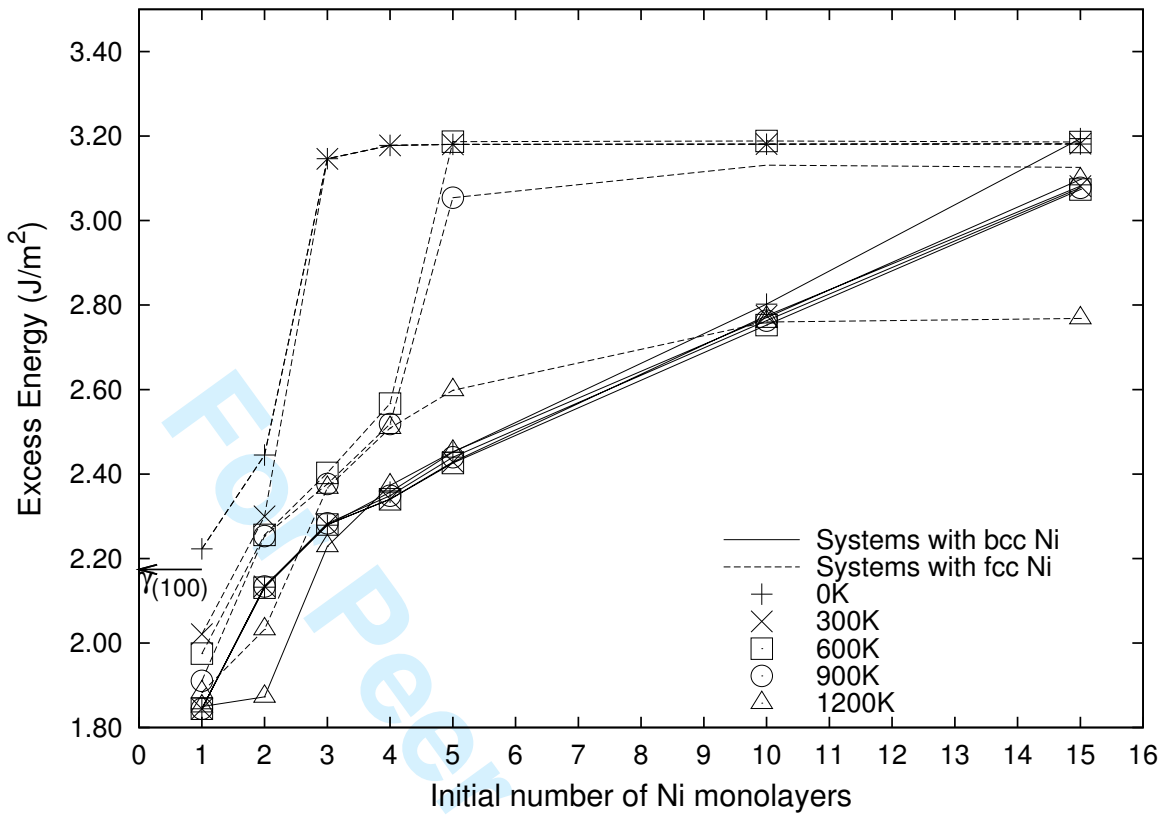


Figure 6. The excess interface energy  $\gamma$  as a function of the initial number of fcc (dashed lines) and bcc (solid lines) Ni on Fe(001) in OR I. The arrow on the abscissa indicates the energy of a free  $\alpha$ -Fe(001) surface. Two regions are clearly visible, below and above 3-4 ML. Above the excess interface energy increases linearly for the bcc systems while it is nearly constant for the fcc systems.

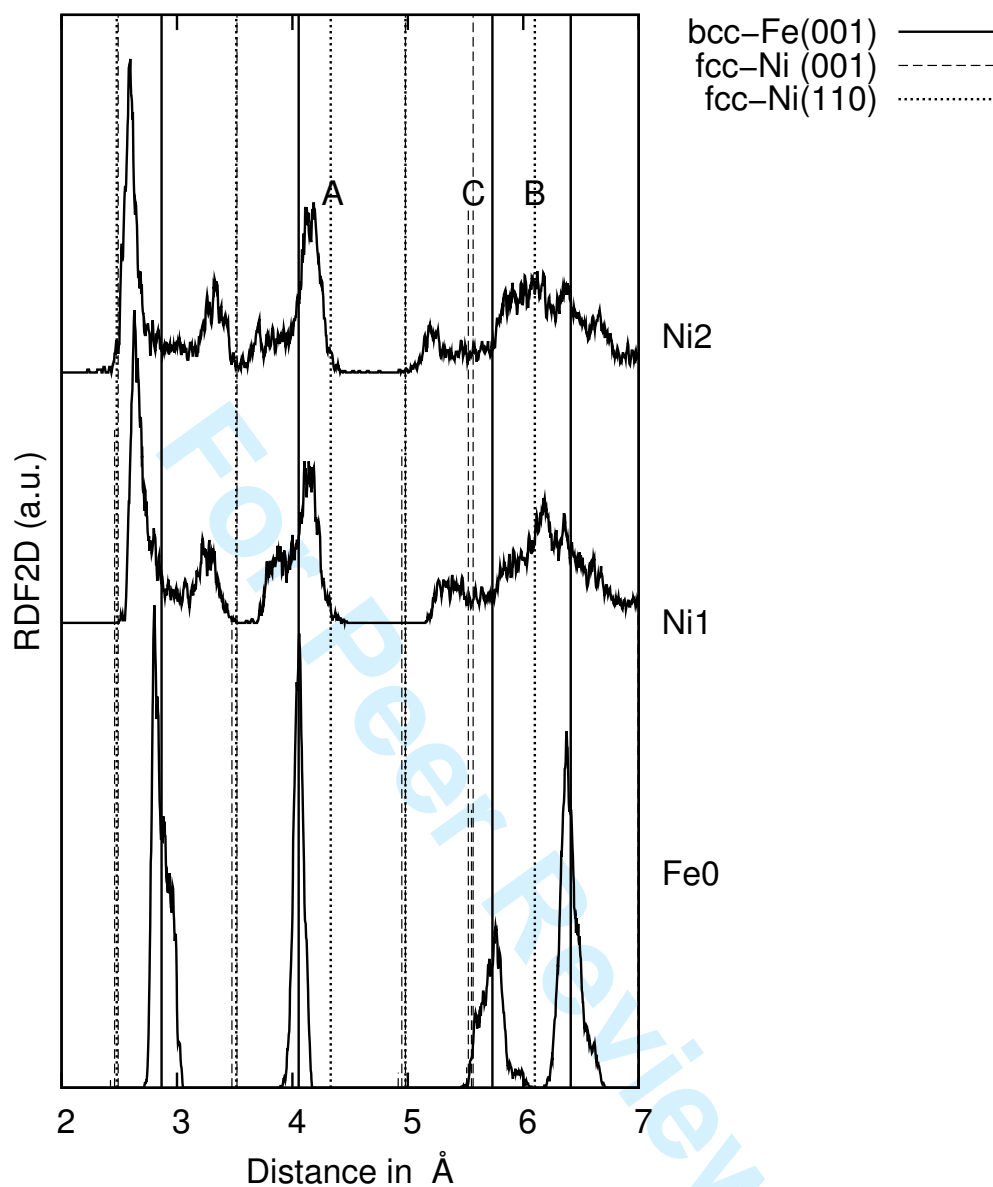


Figure 7. The 2DRDF for layers directly at the interface in the ground-state structure of the system with initially 3 ML of fcc Ni in OR I, shown in Figure 5. The peaks of the fcc-Ni are common for both fcc-Ni (001) and fcc-Ni (110) planes, except of the peaks marked A and B which only belong to the fcc-Ni (110) plane, and the peak marked C which only belong to the fcc-Ni (001) plane, and the peak marked C which only belong to the fcc-Ni (001) plane. Fe0 is the top-most Fe layer of the substrate. Ni1 and Ni2 are the first two Ni layers at the interface.

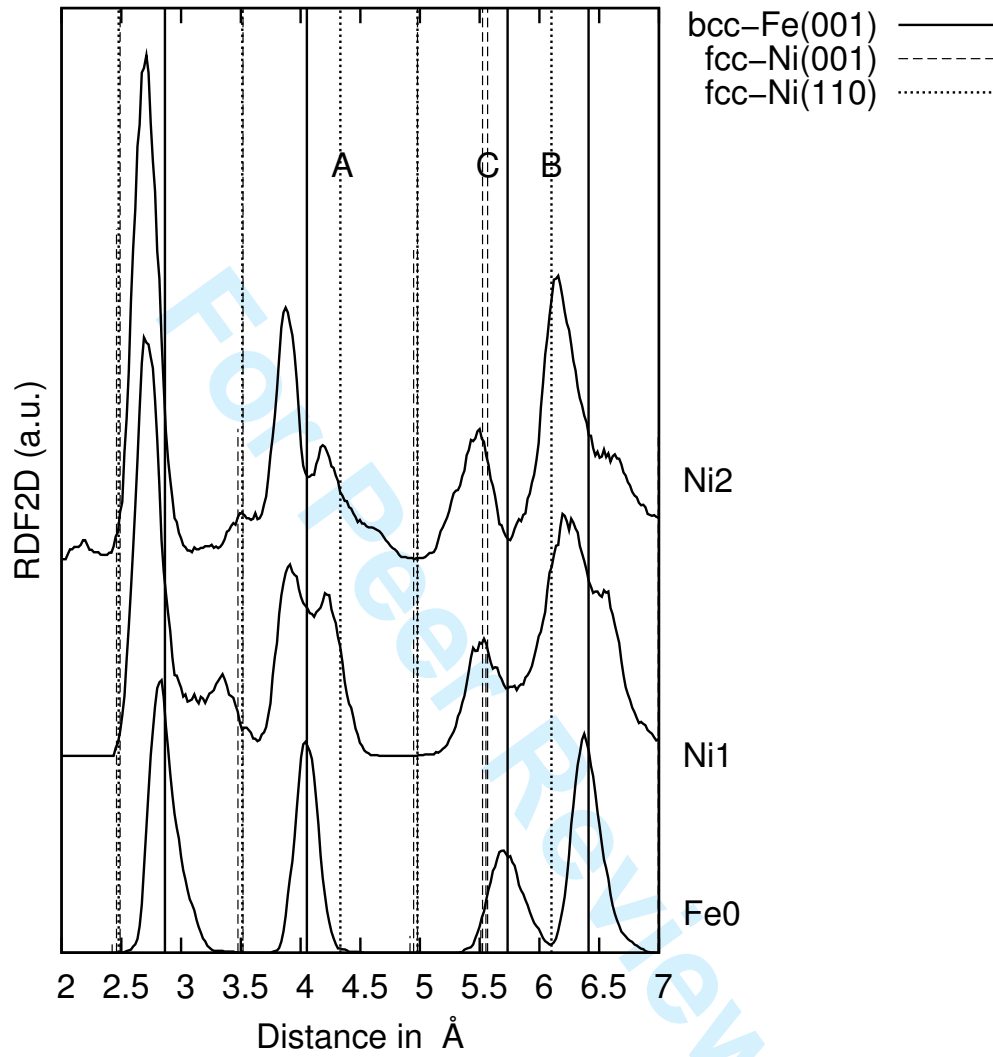


Figure 8. The 2DRDF for the layers directly at the interface in the ground-state structure of the system with initially 2 ML of fcc Ni in OR II. The peaks of the fcc-Ni are common for both fcc-Ni (001) and fcc-Ni (110) planes, except of the peaks marked A and B which only belong to the fcc-Ni (110) plane, and the peak marked C which only belong to the fcc-Ni (001) plane. Fe0 is the top-most Fe layer of the substrate. Ni1 and Ni2 are the first two Ni layers at the interface.

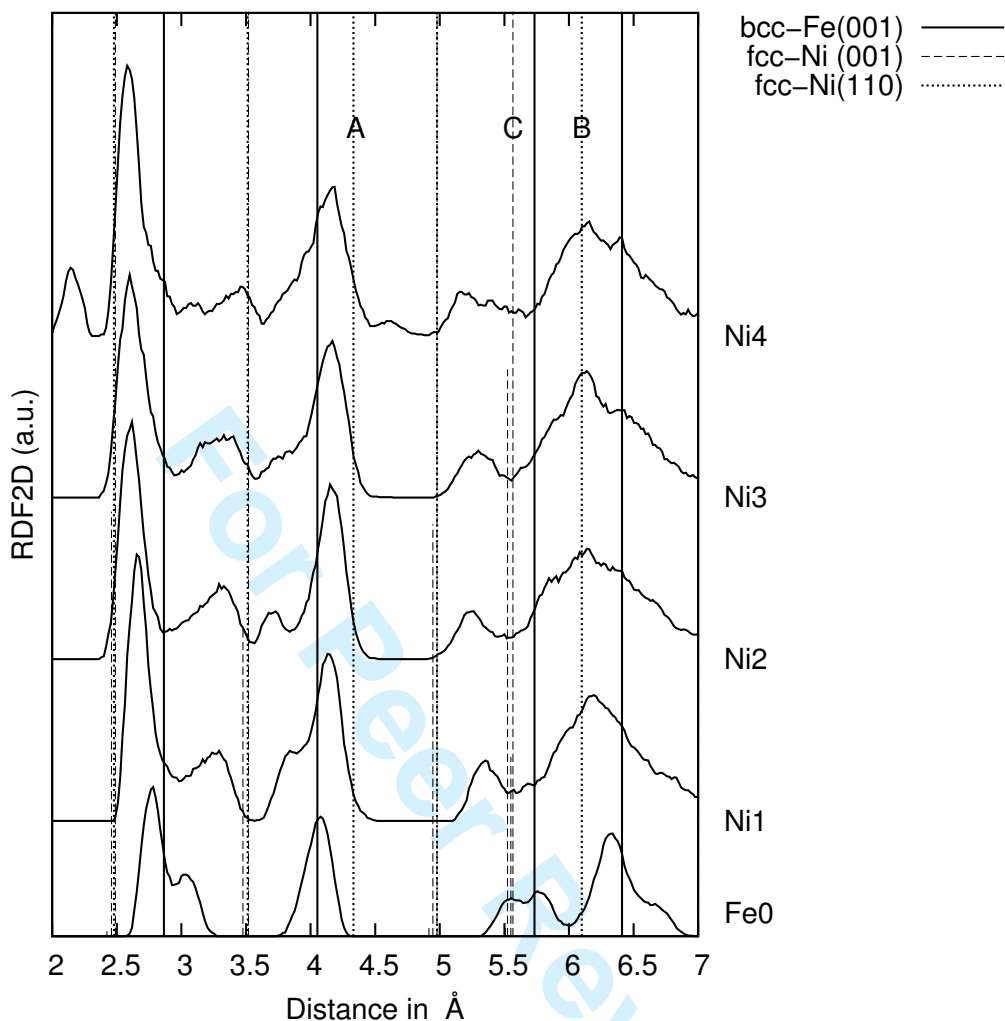


Figure 9. The 2DRDF for the layers directly at the interface in the ground-state structure of the system with initially 4 ML of fcc Ni in OR II. The peaks of the fcc-Ni are common for both fcc-Ni (001) and fcc-Ni (110) planes, except of the peaks marked A and B which only belong to the fcc-Ni (110) plane, and the peak marked C which only belong to the fcc-Ni (001) plane. Fe0 is the top most layer of the substrate. Ni1 to Ni4 are the first four Ni layers at the interface.